



Applied Materials Process Diagnostics and Control Group Wins 2004 Supplier Excellence Award from Texas Instruments

May 19, 2005

SANTA CLARA, Calif., May 19, 2005 (BUSINESS WIRE) -- The Process Diagnostics and Control group at Applied Materials, Inc. has received Texas Instruments' (TI) prestigious 2004 Supplier Excellence Award for the exemplary performance of its inspection and metrology systems. The award honors an elite group of suppliers chosen from among TI's worldwide supplier base that meet its high standards in the areas of cost reduction, environmental responsibility, technology, responsiveness, assurance of supply, and quality. TI presented the award to Applied Materials at a ceremony on May 18, 2005.

Rob Simpson, vice president of Worldwide Procurement and Logistics at TI, said, "This year's award to Applied Materials for its world-class inspection and metrology technologies reflects not only the quality of their products, but also the high integrity, commitment and competence of their employees. Each member of Applied's team is dedicated to providing top notch, world-class service to our facilities. The PDC group has a candid and honest approach to every task that makes us very comfortable in having a close relationship with Applied Materials."

"We are extremely pleased that our complete set of inspection and metrology tools at TI received this award," said Dr. Gilad Almogy, vice president and general manager of Applied Materials' Process Diagnostics and Control product business group. "TI is known for its advanced technical level, highly efficient manufacturing and strong emphasis on quality. Looking forward, Applied is committed to improving all aspects of our performance to offer even greater value to TI, while continuing to provide truly enabling technology that solves emerging defect and yield challenges."

Applied Materials' inspection and metrology products at TI include the Applied ComPlus(TM) family of tools for wafer inspection, the Applied SEMVision(TM) family of defect review tools, some with focused ion beam (FIB) technology for embedded defect and electrical failure analysis, and the Applied VeritySEM(TM) system for critical dimension metrology.

Applied Materials, Inc. (Nasdaq: AMAT), headquartered in Santa Clara, California, is the largest supplier of equipment and services to the global semiconductor industry. Applied Materials' web site is www.appliedmaterials.com.

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